



Automatic Test Committee Chair's Report

Les Orlidge





Slattery Award

- Winner: Michael Dewey
- Award will be presented at Awards Luncheon on Wednesday
 - You can register for lunch separately from Technical program



Upcoming NDIA SED Events

- 20th Annual Systems Engineering Conference Event #8870, October 23-26, 2017 Waterford, Springfield, VA <u>http://www.ndia.org/events/2017/10/23/20th-</u> systems-engineering-conference
- Annual Strategic Planning Session / SED Meeting December 6, 2017 in the Washington, DC area (TBD)



IEEE SCC20

- Ballot Closed P1636 Draft Standard for Software Interface for Maintenance Information Collection and Analysis (SIMICA)
 - This standard is an implementation-independent specification for a software interface to information systems containing data pertinent to the diagnosis and maintenance of complex systems consisting of hardware, software, or any combination thereof.
- Ballot Closed P1636.1 Draft Standard for SIMICA: Exchanging Test Results & Session Information via eXtensible Markup Language
 Via XML and Web Ontology Language (OWL)
- Ballot Closed P1636.2 Draft Standard for SIMICA: Exchanging Maintenance Action Information via eXtensible Markup Language
 - Information associated with the removal, repair, and replacement of system components to maintain/support an operation system



IEEE SCC20

- Recirculation Ballot Closed P1671.1 Draft Standard for Automatic Test Markup Language (ATML) Test Description
 - Defines an exchange format, utilizing XML, for specifying test performance, test conditions, diagnostic requirements, and support equipment to locate, align, and verify the proper operation of a Unit Under Test (UUT).
- Recirculation Ballot Closed P1671.3 Draft Standard for Automatic Test Markup Language (ATML) Unit Under Test (UUT) Description
 - Defines an exchange format, utilizing XML, for both the static description of unit under test (UUT), and the specific description of UUT instance information.



IEEE SCC20

 Recirculation Ballot to Open - P1871.2 Draft Recommended Practice for IEEE 1671 Test Equipment Templates and Extension Classes for Describing Intrinsic Signal Path Information for Cables, Interface Adapters and Test Equipment

Purpose:

- To document and enable programmatic access to the intrinsic characteristics of path related resources found in automated test systems via ATML
- To show best practices in how to extend ATML in order to gain access to more detailed intrinsic path characteristics that applications often require